

# ILC Cherenkov Detector: Photodetector Studies

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## 1 Theory & Practice

- Non-linearity definitions: DNL & INL
- Test facility setup

## 2 Linearity Measurements

- Readout electronics: QDC
- Photodetector spectra & QDC correction
- PDs: INL methods
- PDs: DNL methods

## 3 Long-term Stability

- Measurements & corrections
- Applicable at the ILC?

## 4 Summary & Outlook

# ILC Polarimetry Concept



Two Compton polarimeters per beam are foreseen in the BDS system.  
**One** upstream & **one** downstream of the collider  $e^+e^-$  IP.

Reminder: We want to do precision physics  
Thus, we **need** precise measurements of the beam polarisation.

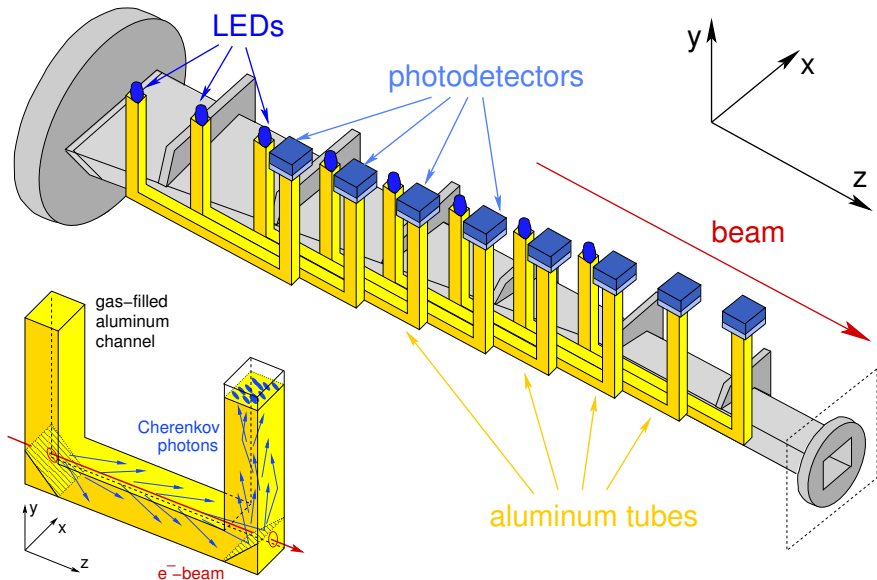
**Hoping to achieve:**  $\frac{d\mathcal{P}}{\mathcal{P}} = 0.25\%$  **per polarimeter**

SLD polarimeter: achieving this goal is limited by systematics effects  
→ detector linearity is a crucial factor!

Need Cherenkov detector with exceptional linearity!

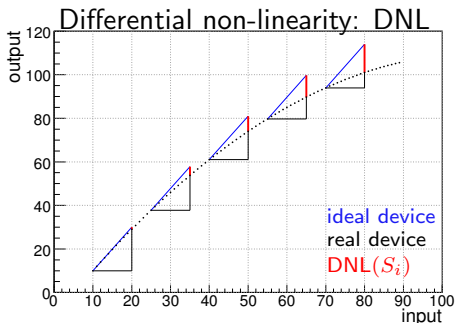
⇒ **Study photodetectors (PD) & electronics (QDC) in test setup!**

## Cherenkov Detector for ILC Polarimetry

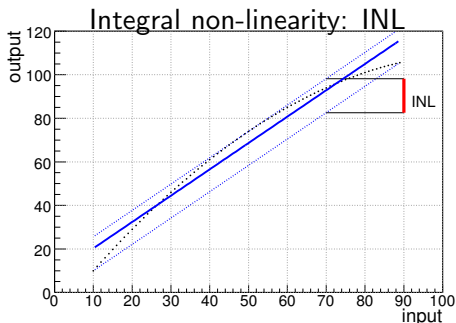


# Theory & Practice

# Definitions of DNL and INL



response  $R$  to fixed change  $\Delta S$  in signals  $S_i$  and  $S_i + \Delta S$  dep. on  $S_i$

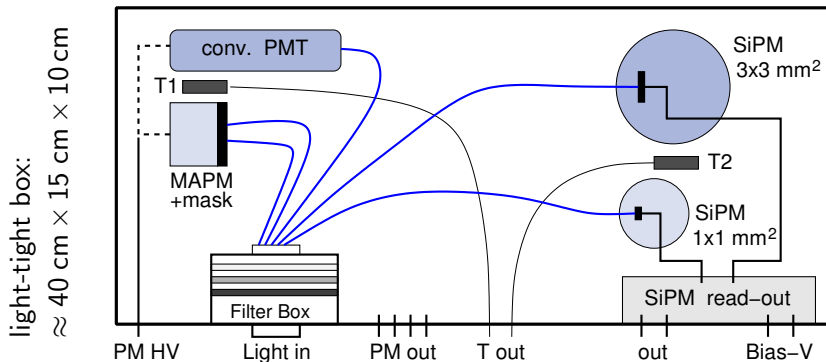


maximal deviation (add  $\pm$ dev.) between data & straight line fit

$$\left. \begin{array}{l} \text{Ideal: } R_{S_i+\Delta S} = R_{S_i} + R_{\Delta S} \text{ indep. of } S_i \\ \text{Real: } R_{\Delta S} \text{ depends on } S_i \end{array} \right\} \Rightarrow \text{DNL}(S_i) = \frac{R_{\Delta S}(S_i)}{R_{\Delta S}^{\text{ideal}} - 1}$$

$R_{\Delta S}^{\text{ideal}}$  needed: okay for QDC, where  $R_{\Delta S}^{\text{ideal}} = 1$  LSB (least significant bit), but it's usually unknown for PDs  $\rightarrow$  use mean of all recorded  $R_{\Delta S}(S_i)$

# Test Facility

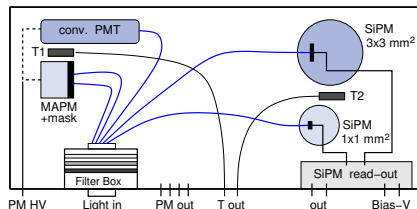


- mountings for several PDs available: conv. PM, **MAPM**, SiPM
- function generator controlled **blue LED** ( $\lambda_{peak} = 470 \text{ nm}$ ,  $FWHM = 35 \text{ nm}$ ) + optical fibers + choice of different optical filters (attenuation)
- readout: 8-channel, 12-bit QDC with dual ranges (high, low)  
*high*:  $0..800 \text{ pC} \leftrightarrow 200 \text{ fC LSB}$       and      *low*:  $0..100 \text{ pC} \leftrightarrow 25 \text{ fC LSB}$

# What is the Objective?

Want to...

- measure PD (non-)linearities with sub-percent accuracy
- establish measurement methods sensitive to this level for both DNL & INL measurements
- develop procedures to correct possible non-linearities (mostly DNL)
- apply correction procedures to repeated a/o long-term measurements to test & refine both (meas. methods and correction procedure)



Although several PDs could be tested, concentrate on one type only.

⇒ **Study type R5900U-00-M4 (Hamamatsu, 2×2 MAPM) thoroughly!**



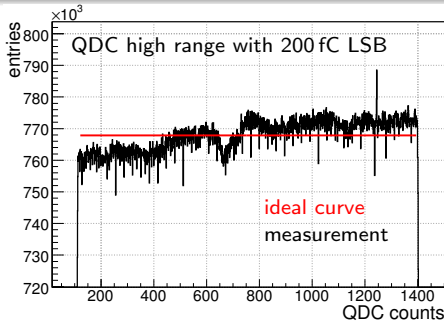
# Linearity Measurements

# QDC non-linearities

inspired by:  
Maxim, Application Note 2085, 2003



- long, slow (10 Hz) ramp waveform as input signal → test channel  
(covers high range up to 1500 QDC-cts)
- short, fast ( $\approx 20$  kHz) random gate triggered by white noise (function gen.)
  - ▷ short → high sampling rate
  - ▷ fast & random → avoid phase effects
 on average: 2000 samples per ramp
- actual/ideal bin width → DNLs  
DNLs  $\approx 0.01$  LSB in high range  
(low/high bins generally narrower/wider)
- sum DNLs up to  $n^{th}$  bin → INL  
INL  $\approx 3$  LSBs  $\approx 1\%$  in high range

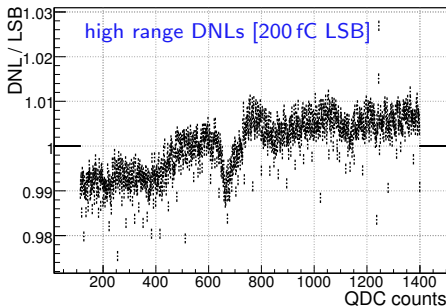


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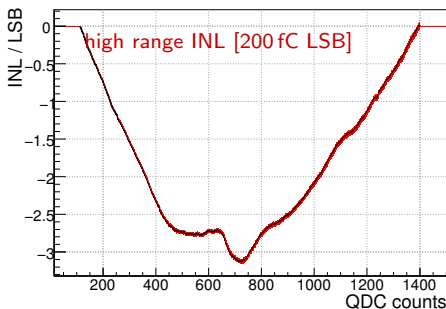
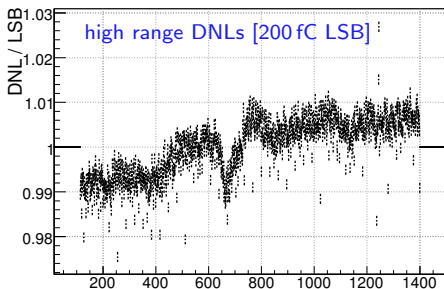


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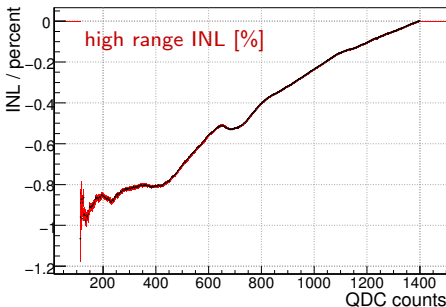
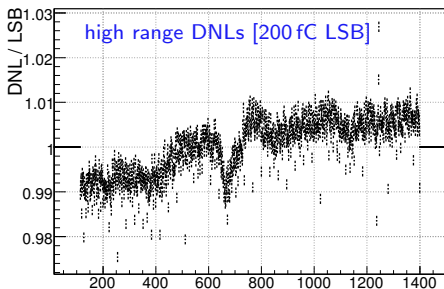


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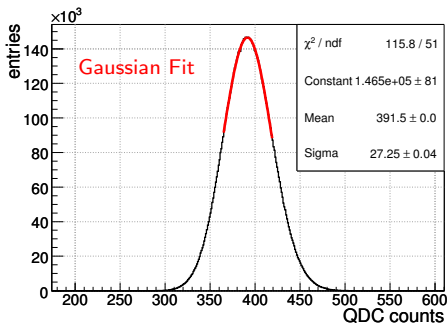
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# PD spectrum & QDC correction



- PD spectrum in QDC high range no sharp peak, but **Gaussian shape** from fluctuations in  $N^\gamma$  (LED) and PD gain variations
- apply DNL correction to spectrum weigh contents of each QDC bin by  $1/\text{DNL}$  → reduces contents of wider bins, vice-versa

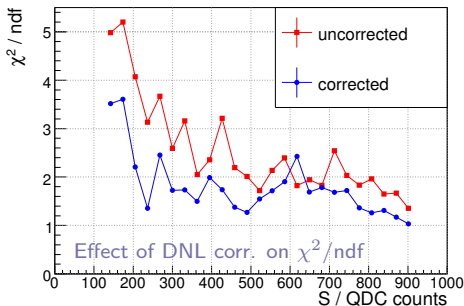


Typical PD spectrum as recorded in QDC high range (200 fC LSB)

- ▷ account for warm-up phases of:
  - PD: 5h, LED: 2h prior to measuring
- ▷ always use same anode of  $2 \times 2$  MAPM
- ▷ minimize stat. errors → 10 million ev.

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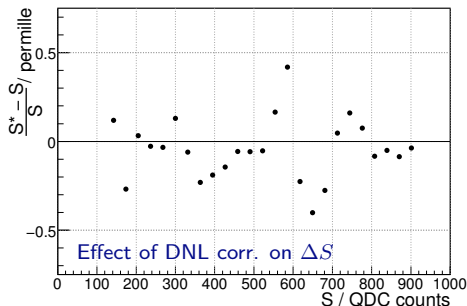
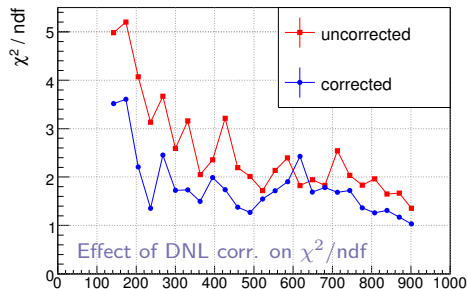
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▷  $\chi^2/\text{ndf}$  of gaussian fit



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- check a series of 25 PD spectra ⇒ effects are minute!
  - ▷  $\chi^2/\text{ndf}$  of gaussian fit
  - ▷ relative change of peak position:
 
$$\Delta S = \frac{S^* - S}{S} \lesssim 0.02\% \text{ (mostly)}$$
 Corr. causes 0.05% effect only close to the large dip in the DNL distr. (600-700 QDC cts.)





# PD: Signal Modelling



- **Multi-Poisson fit model:**

**pros:** determines  $N^{p.e.}$  and gain, but PD linearity vs. output charge suffices

**cons:** time consuming; very susceptible to slight changes in initial conditions

- **Gaussian fit model:**

**pros:** robust method; determines  $N^{p.e.}$

**cons:** uses only a narrow region of the signal peak ( $\pm 1$  rms)

- **Goodness of fit:**

$$\Lambda = \frac{\sigma^{\text{gauss}}}{\sqrt{Q_{\text{QDC}} - \text{DC}}}$$

with dark current (prev. measured):

DC = 62.5 QDC counts

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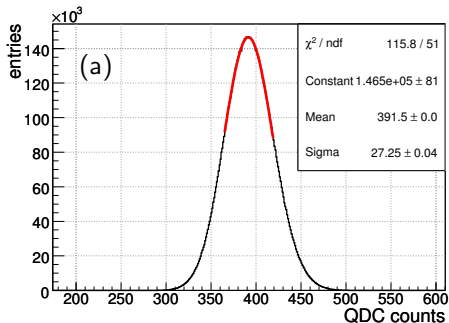
$$\Lambda = \frac{\sigma^{\text{gauss}}}{\sqrt{Q_{\text{QDC}} - \text{DC}}}$$

with dark current (prev. measured):

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$$\chi^2 / \text{ndof} = 116 / 51$$

$$\Lambda = 1.502$$



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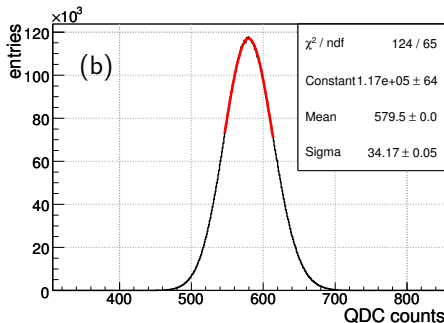
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$$\chi^2 / \text{ndof} = 124 / 65$$

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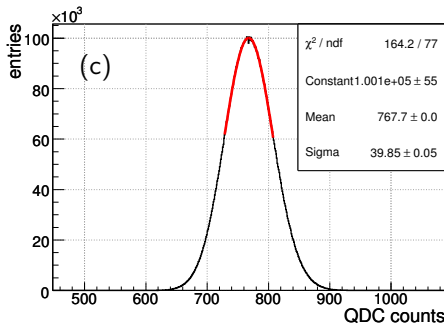
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with dark current (prev. measured):

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$$\chi^2 / \text{ndof} = 164 / 77$$

$$\Lambda = 1.501$$



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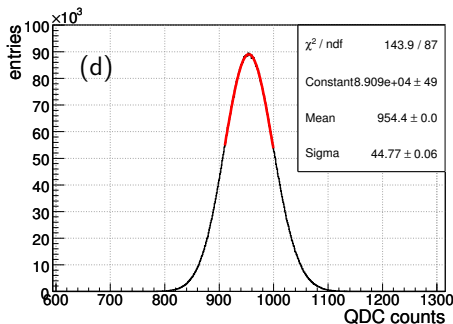
$$\Lambda = \frac{\sigma^{\text{gauss}}}{\sqrt{Q_{\text{QDC}} - \text{DC}}}$$

with dark current (prev. measured):

DC = 62.5 QDC counts

$$\chi^2 / \text{ndof} = 144 / 87$$

$$\Lambda = 1.499$$



# PD: Measuring INL (2 methods)



## 'Optical Filters':

- used to attenuate light from the LED by a fixed/known(?) amount
- filter calibration not precise enough
- method discarded for now (→ backup)

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- want to ensure a **linear variation of light** on PD cathode
- need to vary LED light output linearly → how?
- operate LED with a function generator, using rectangular pulses
- vary pulse lengths linearly: 30...150 ns, in 5 ns steps
  - ▷ minimal pulse length must be longer than LED rise & fall times of  $\approx 5$  ns
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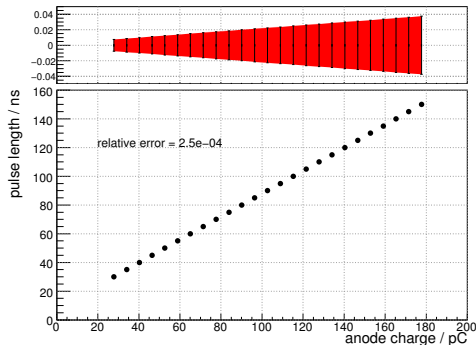
# 'Pulse-Length' method $\rightarrow$ INL

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LED:  $f = 10$  kHz,  $U = -5$  V; QDC: gate width 200 ns; PD: bias voltage  $U_{HV} = -800$  V
- single measurement:  $10^7$  LED pulses  $\rightarrow$  minimise statistical errors
- systematic uncertainties  $\rightarrow$  study two sources
  - ▷ pulse length accuracy  $\Delta t/t$
  - ▷ fitting procedure ( $\chi^2$ )
- straight-line fit to central part  
 $\chi^2$ -test to find correct order of magnitude for syst. errors  
( $\chi^2 \approx 1$ , if errors okay & assuming the pulse inaccuracy is the only source)
- initial inaccuracy:  $10^{-3}$   
syst. error:  $\Delta t/t = 10^{-4}$

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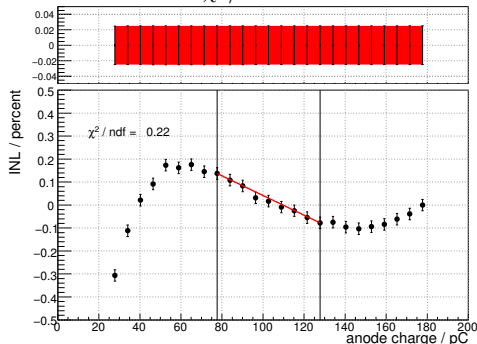
first iteration of  $\chi^2$ -test  
relative error =  $2.5 \cdot 10^{-4}$



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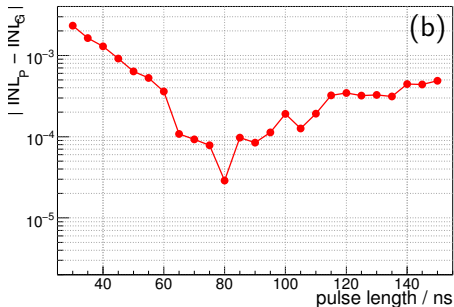
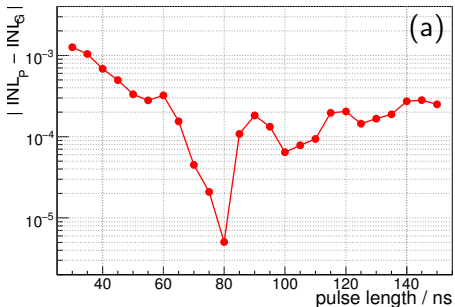
first iteration of  $\chi^2$ -test  
 $\chi^2/\text{ndof} = 0.22$



# Influence of Fit Methods on INL



Fit PD spectrum with either the Multi-Poisson, or the Gauss fit model  
 → study systematic influence of the fit model on the derived INL

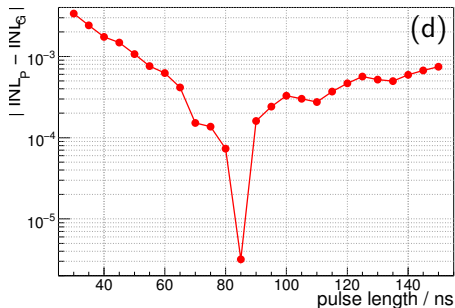
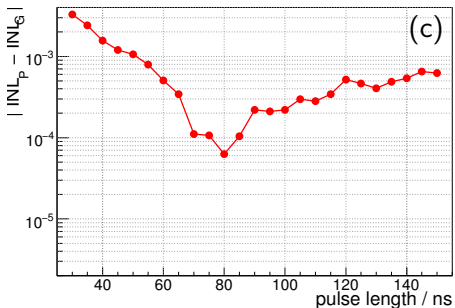


Prominent dip at a pulse length of 80..100 ns → corresponds to the zero-crossing of the INL ⇒ equally well reproduced by both methods

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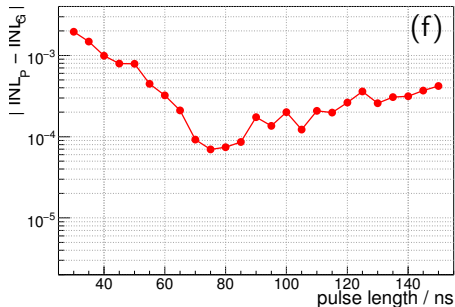
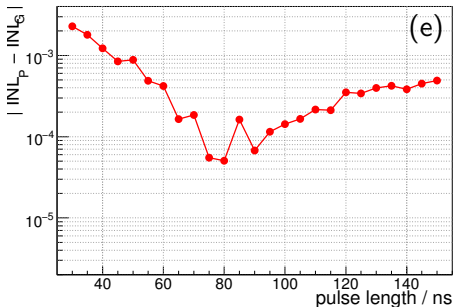
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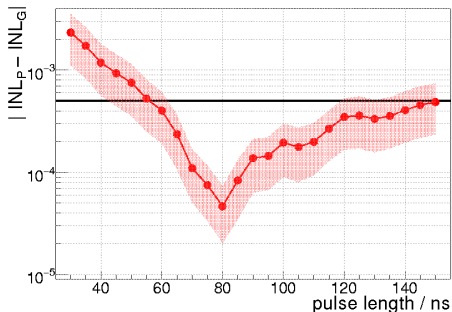


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 Find estimate of the uncertainty of one fit model → average results?

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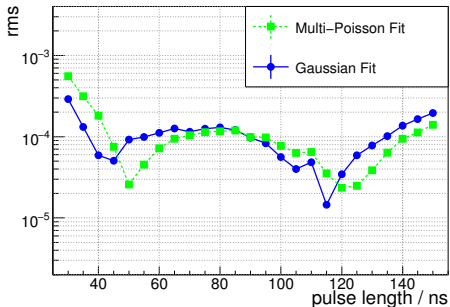


Difference averaged over 7 measurement series and both fit methods.  
⇒ **systematic uncertainty due to fitting procedure:  $5 \cdot 10^{-4}$**

# Influence of Fit Methods on INL (cont'd)



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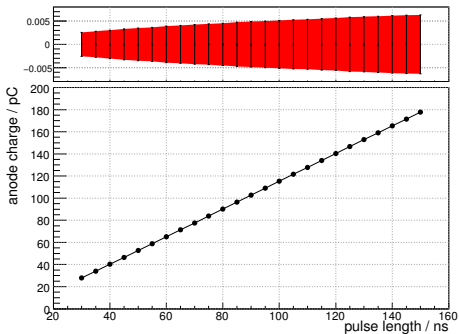
RMS of 7 series of measurements: **Multi-Poisson** vs. **Gauss** fit model  
 Difference between both fit models is an order of magnitude smaller  
 than differences within each method ⇒ **negligible!**



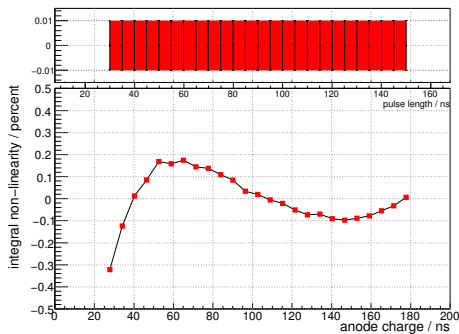
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INL from '*Pulse-Length*' measurement + all systematic uncertainties of pulse length inaccuracy ( $10^{-4}$ ) and fitting procedures ( $5 \cdot 10^{-4}$ ).



'*Pulse-Length*' measurement with statistical errors only !

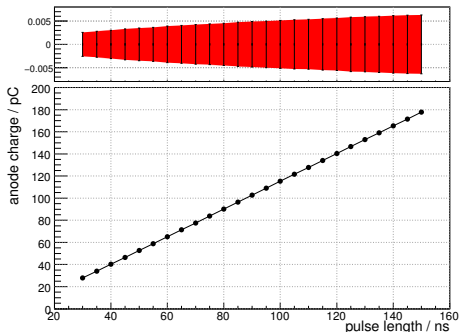


from measurement derived INL with statistical errors only

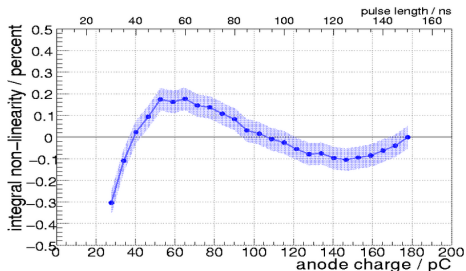
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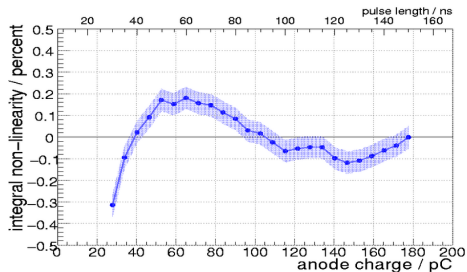
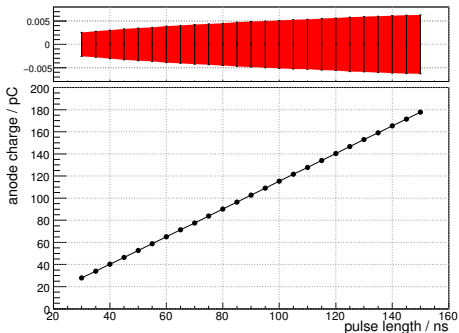


from measurement derived INL  
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'*Pulse-Length*' measurement  
with statistical errors only !

from measurement derived INL  
+ PD systematics + DNL(QDC)

**INL is measured & controlled with accuracy:  $INL = (0.5 \pm 0.05)\%$**

# PD: Measuring DNL (2 methods)



## 'Double-Pulse' method:

- use two LEDs: LED1 as in '*Pulse-Length*' method  
LED2 operated with a fixed, very short pulse
- compare signals pulsing: both LEDs simultaneously ↔ only LED1  
(simultaneity achieved using synchronised output channels (function gen.):  $f = 10$  kHz)  
LED1:  $U = -5$  V, pulse length:  $t_1 = 30..150$  ns (5 ns steps)  
LED2:  $U = -2$  V, pulse length:  $t_2 = 25$  ns, fix

## 'E158' method:

(inspired by: E158 collaboration, Technical Note No.67, 2005)

- use two LEDs ( $f = 10$  kHz,  $U = -5$  V), both operated with fixed pulses
- compare signals pulsing: both LEDs simult. ↔ LED1+LED2 sep.  
LED1: pulse length:  $t_1 = 50$  ns  
LED2: pulse length:  $t_1 = 150$  ns } results in QDC signals with  
a ratio of  $Q_1/Q_2 \approx 1/4$   
(charge ratio  $\neq 1/3$  due to different LED performance a/o coupling to optical fibers)
- attenuate LED light intensity with optical filters → measure DNLs  
(actual attenuation is not relevant → no filter transmission coefficients are needed)

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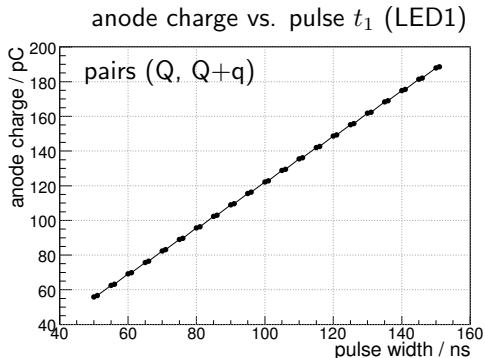
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# 'Double-Pulse' method → DNL

- vary signals using two LEDs: variable pulse + fixed pulse  
 LED1:  $U = -5 \text{ V}$ , pulse length:  $t_1 = 30..150 \text{ ns}$  (5 ns steps) →  $Q(t_1)$   
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- single measurement:  $10^7$  LED pulses → minimise statistical errors

- use parametrised function of a perfectly linear PD to fit the data
- **insufficient accuracy!**  
 DNLs up to 10% → bias(?) or faulty measurement?  
 (several causes investigated → excluded)
- method discarded . . .



# 'Double-Pulse' method → DNL

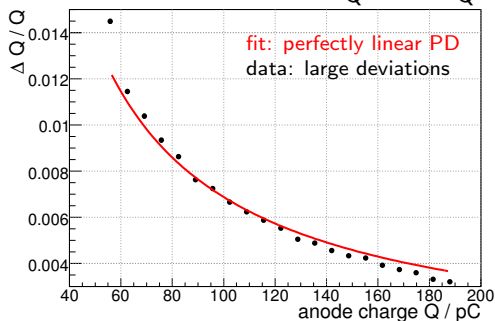
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fix pulse effect:  $\frac{(Q+q) - Q}{Q} = \frac{q}{Q}$





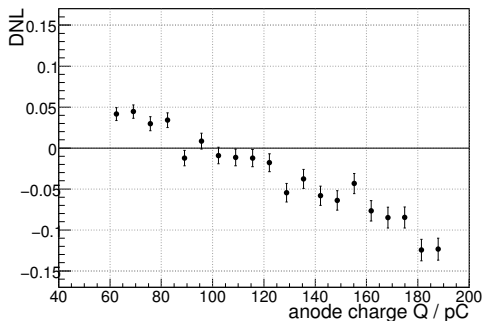
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**DNLs up to 10%**



# 'E158-method' → DNL

- vary signals using 3 LED config's (fixed pulses) + 8 filters (for attenuation)

LED1: fixed pulse length:  $t_1 = 50$  ns →  $Q_1$

LED2: fixed pulse length:  $t_2 = 150$  ns →  $Q_2$

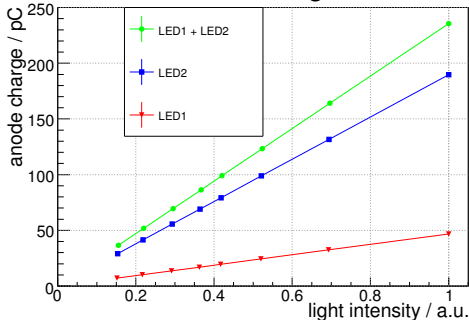
LED1+LED2: →  $Q_{1+2}$

- single measurement:  $10^7$  LED pulses  
→ minimise statistical errors

● calculate  $DNL = \frac{Q_{1+Q_2}}{Q_{1+2}}$

- **good accuracy:**  
mostly DNLs  $\lesssim 0.5\%$

'E158' anode charge  
3 LEDs config's + 8 filters



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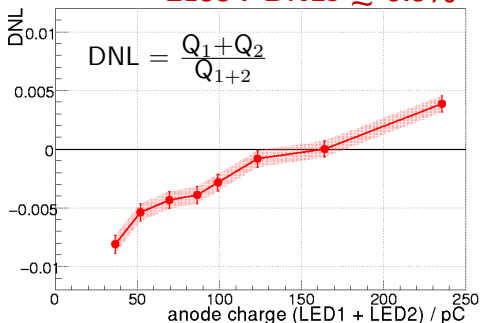
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**'E158': DNLs  $\lesssim 0.5\%$**



# 'Pulse-Length' → DNL Interpretation

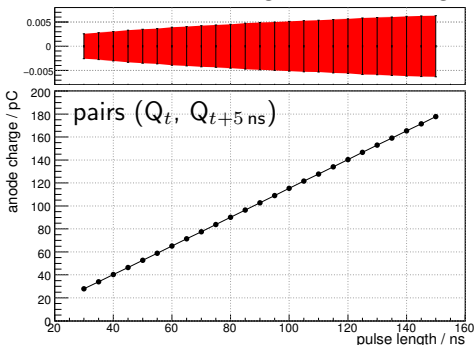
- 'Double-Pulse' DNL interpretation of 'Pulse-Length' measurement  
only one LED1: varied pulse length:  $t_1 = 30..150$  ns; equal 5 ns steps (fix)  
→ assume signals for consecutive pulse lengths as pairs ( $Q_t, Q_{t+5\text{ ns}}$ )
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- use parametrised function of a perfectly linear PD to fit the data:

- calculate for pairs:

$$\frac{Q_{5\text{ ns}}}{Q} = \frac{(Q_t + Q_{t+5\text{ ns}}) - Q_t}{Q_t}$$

'Pulse-Length' anode charge



# 'Pulse-Length' → DNL Interpretation

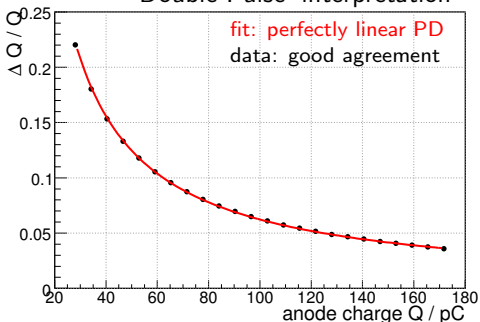
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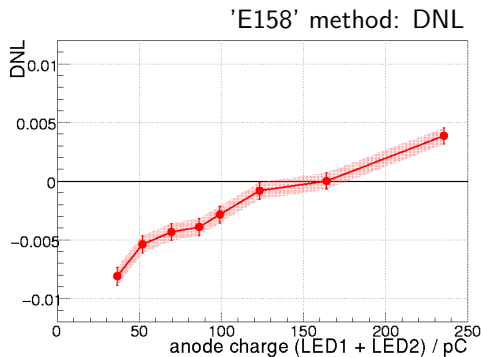
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## 'Double-Pulse' interpretation



# DNL Comparison: 'E158' vs. 'Pulse-Length'

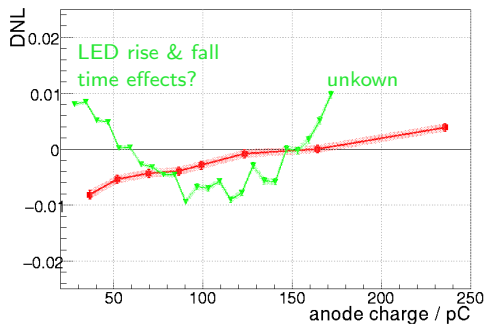
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- 'E158' method measures DNLs at  $\lesssim 0.5\%$  level
- 'Double-Pulse' Interpretation of 'Pulse-Length' signals yields similar accuracy!  
⇒ mostly DNL  $\lesssim 0.5\%$



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'E158' & 'Double-Pulse': DNL



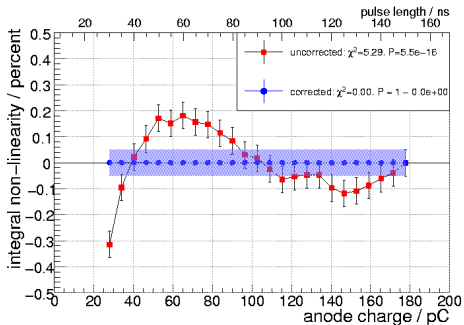
# Long-term Stability & Corrections



# Long-term Stability I

Using a single reference measurement for the correction:

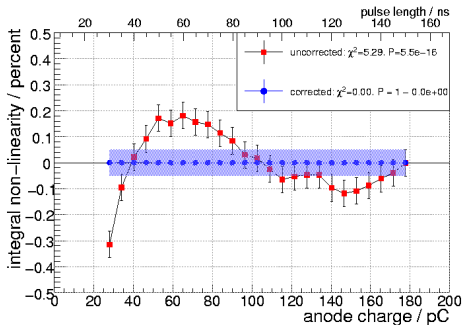
(e) reference measurement: 0 h



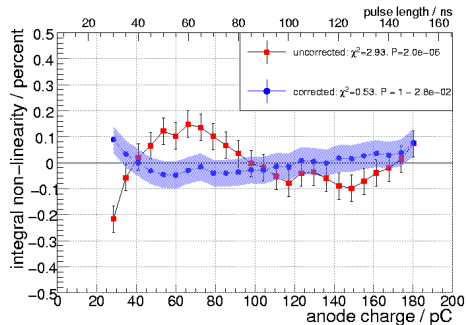
# Long-term Stability I

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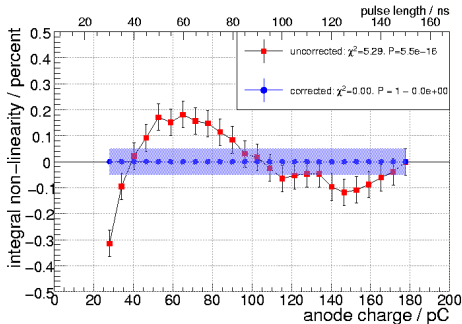
(a) -74 h (-3 days)



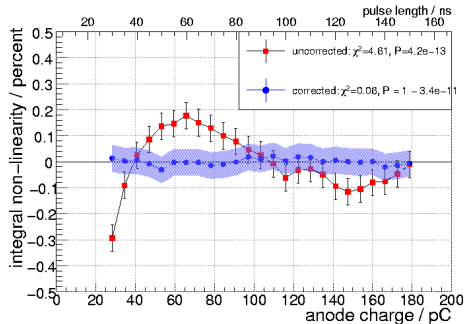
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Using a single reference measurement for the correction:

(e) reference measurement: 0 h



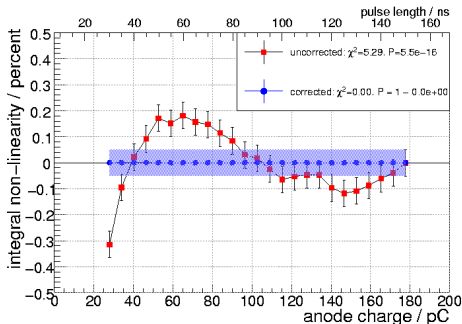
(b) -60 h (-2.5 days)



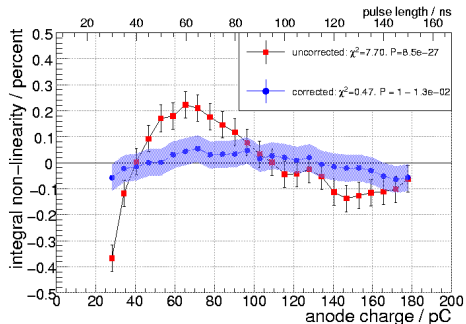
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(e) reference measurement: 0 h



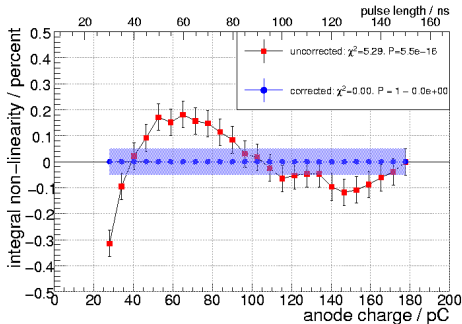
(c) -46 h (-2 days)



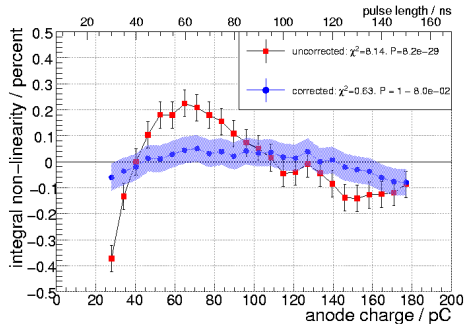
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Using a single reference measurement for the correction:

(e) reference measurement: 0 h



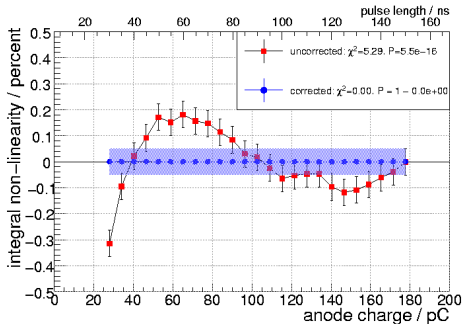
(d) -31 h (-1 days)



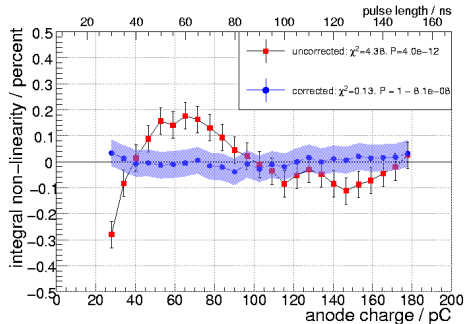
# Long-term Stability

Using a single reference measurement for the correction:

(e) reference measurement: 0 h



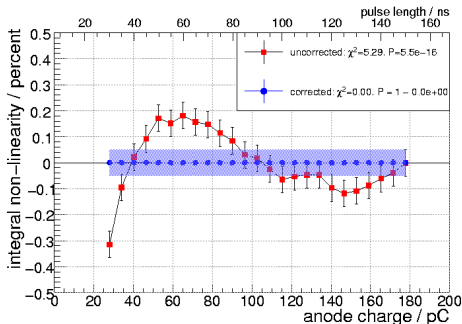
(f) +24 h (+1 days)



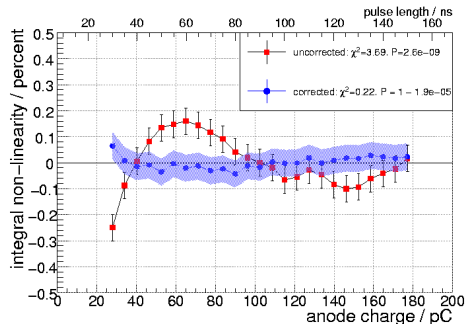
# Long-term Stability I

Using a single reference measurement for the correction:

(e) reference measurement: 0 h



(g) +92 h (+4 days)



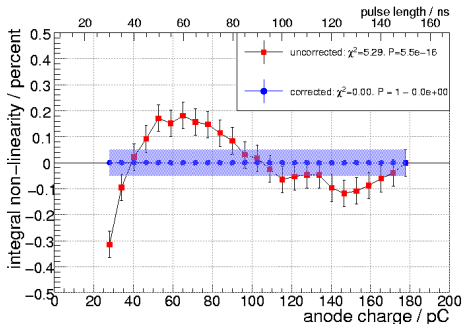
**Successful INL correction for data recorded up to 7 days apart!**

⇒ measured & controlled to an accuracy of  $\text{INL} \leq 0.1\%$

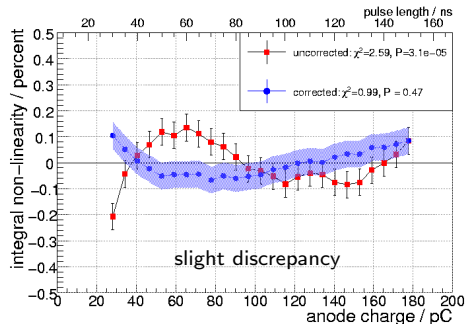
# Long-term Stability I

Using a single reference measurement for the correction:

(e) reference measurement: 0 h



(h) +168 h (+7 days)



**Successful INL correction for data recorded up to 7 days apart!**

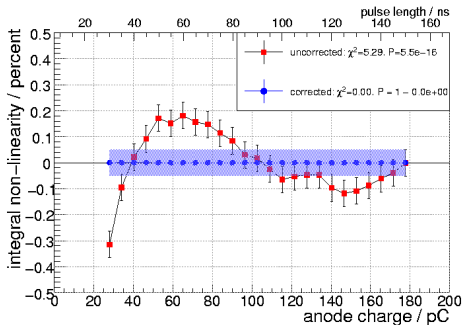
⇒ measured & controlled to an accuracy of  $\text{INL} \lesssim 0.1\%$



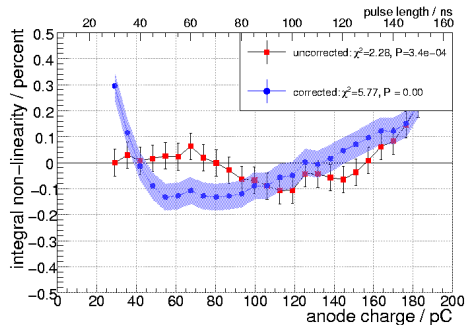
# Long-term Stability I

Using a single reference measurement for the correction:

(e) reference measurement: 0 h



(i) +672 h (28 days)

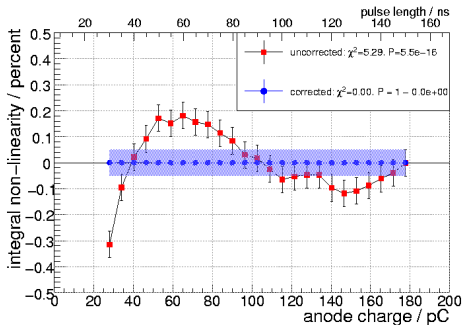


Data recorded much later than the reference measurement cannot be corrected successfully anymore → **reference measurements need to be taken regularly & not more than a week apart!**

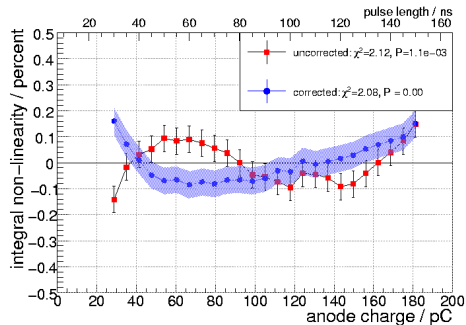
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Using a single reference measurement for the correction:

(e) reference measurement: 0 h



(j) +696 h (29 days)

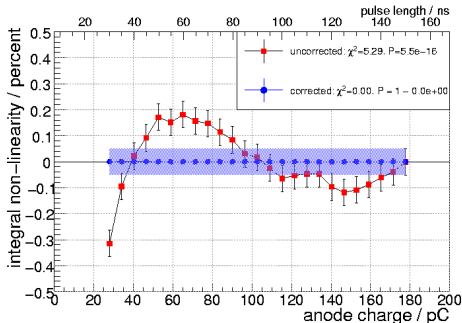


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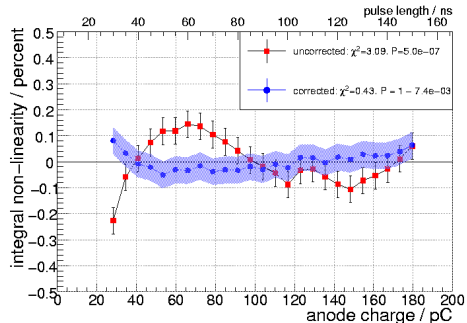
# Long-term Stability I

Using a single reference measurement for the correction:

(e) reference measurement: 0 h



(k) +718 h (30 days)

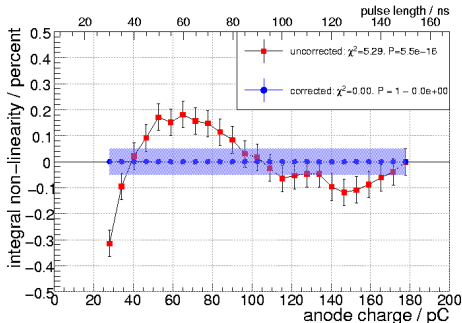


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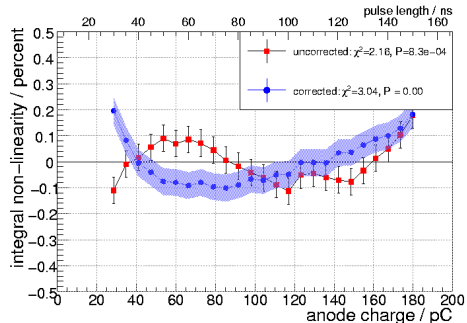
# Long-term Stability I

Using a single reference measurement for the correction:

(e) reference measurement: 0 h



(l) +839 h (35 days)



Data recorded much later than the reference measurement cannot be corrected successfully anymore → reference measurements need to be taken regularly & not more than a week apart!

# Long-term Stability II



PD (non-)linearity is intrinsic quality  $\rightarrow$  should not change over time  
Not only PD is studied, **but entire setup for calibration measurements!**

The data recorded more than seven days after the previously used reference measurement could be **successfully corrected** using a more recent measurement as reference!

Could this be used in an ILC environment?

- **YES.** presented calibration/correction procedure is also applicable to data from an ILC Cherenkov detector
- could take reference measurements (LED calibration runs) between ILC runs, or even in between consecutive trains ( $\Delta t_{\text{trains}} \approx 200$  ms)
  - ▷ readout frequency  $\approx 20$  kHz  $\rightarrow \approx 4000$  LED pulses during  $\Delta t_{\text{trains}}$
- cumulate sufficient statistics for to be used as reference
- use sliding average over most recent couple of measurements

$\Rightarrow$  **An up-to-date calibration at all times can be guaranteed!**

# Conclusions & Outlook

# Conclusions



- Polarisation measurements at the ILC will be limited by systematic effects, not by statistics
- One crucial factor is the linearity of the Cherenkov detector, especially the linearities, both DNL & INL, of the utilised PDs
- Several methods to measure QDC & PD linearities were developed
- QDC linearity: DNLs & INL can be controlled at 0.1% level
- PD linearity: two methods were successfully established
  - ▷ 'Pulse-Length' method measuring  $INL = (0.5 \pm 0.05)\%$
  - ▷ 'E158' method: measuring DNLs also at a level of 0.1%
- Long-term stability & reproducibility were studied ('Pulse-Length' method)  
(Although a definite time dep. was observed, the PD non-linearities could still be successfully corrected for measurements taken a week apart.)

- Variations of the pulse length might still influence the linearity of the device under study, i.e. LED  $\rightarrow$  PD  $\rightarrow$  QDC
- Limited dynamic range of the '*Pulse-Length*' method can be expanded by gradually increasing the LED amplitude voltage
- Both methods & the presented correction procedures can also be applied to an ILC polarimeter Cherenkov detector  
(between, or even during physics runs, using the foreseen LEDs for calibration)